

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	2807	313/582-587.ccls.	US-PGPUB; USPAT	OR	ON	2007/12/09 20:33
L4	119	(batch mass) and (display panel) and (light ((field electron) near3 (emission emitting emissive emitter source))) and (tolerance quality) and (assembly\$3 manufact\$3 fabricat\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/09 20:48
L5	1	1994-335589.NRAN.	DERWENT	OR	ON	2007/12/09 20:44
L6	752	(b(manufact\$3 product\$3) near3 line) and (display panel) and (light ((field electron) near3 (emission emitting emissive emitter source))) and (tolerance quality) and (assembly\$3 manufact\$3 fabricat\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/09 20:48
L7	33	((manufact\$3 product\$3) near3 line) and (display panel) and (light ((field electron) near3 (emission emitting emissive emitter source))) and (tolerance quality) and (assembly\$3 manufact\$3 fabricat\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/09 20:49
L8	43	((manufact\$3 assembly\$3 product\$3) near3 line) and (display panel) and (light ((field electron) near3 (emission emitting emissive emitter source))) and (tolerance quality) and (assembly\$3 manufact\$3 fabricat\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/09 21:17
L9	1	"6302754".pn.	US-PGPUB; USPAT	OR	ON	2007/12/09 21:18
L10	1	"3602754".pn.	US-PGPUB; USPAT	OR	ON	2007/12/09 21:18
L11	28	("2933648" "3265892" "3505046").PN. OR ("3602754").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/12/09 21:18
L12	39	("3013182" "3262010" "3562737" "3589789" "3602754" "3612938" "3617796" "3617803").PN. OR ("3704386").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/12/09 21:22
L13	9	("3704386" "4563617" "5808403" "5939826" "6577056").PN. OR ("6791264").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/12/09 21:33
L14	1	"5862054".pn.	US-PGPUB; USPAT	OR	ON	2007/12/09 21:33

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S1	1	"20010048110"	US-PGPUB; USPAT	OR	ON	2007/12/08 14:39
S2	126	"445"/\$.ccls. and (((inspect\$3 detect\$3 test\$3) with (point station stage step level time period phase)) same (tolerance requirement measurement))	US-PGPUB; USPAT	OR	ON	2006/01/23 16:01
S3	18	("1955794" "3004649" "3340358" "3369201" "3961241" "3978713" "4080836" "4179778" "4522071" "4573934" "4641196" "4643027").PN. OR ("4850921").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 15:32
S4	179	"445"/\$.ccls. and (((inspect\$3 detect\$3 test\$3) with (point station stage step level time period phase)) same (tolerance defect\$3 requirement measurement))	US-PGPUB; USPAT	OR	ON	2006/01/23 15:34
S5	12	("4377890" "4850921" "4871415" "4989072" "5019004" "5059147" "5145432" "5343803" "5725977" "5762528" "5873759" "6085183").PN. OR ("6520818").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 15:51
S6	172397	((inspect\$3 detect\$3 sampI\$3 test\$3) same (point ((assembly produc\$5) near3 line) station stage step level time interval period phase) same (tolerance fault\$3 quality performance requirement measurement))	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:15
S7	2351	((inspect\$3 detect\$3 sampI\$3 test\$3) same (point ((assembly produc\$5) near3 line) station stage step level time interval period phase) same (tolerance fault\$3 quality performance requirement measurement)) and (electro\$luminescen\$3 EL LED OLED light\$emitting light\$emission light\$emissive (light near3 (emitting emission emissive)) and (device display panel))	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:16
S8	1738	((((inspect\$3 detect\$3 sampI\$3 test\$3) with (tolerance fault\$3 quality performance requirement measurement measuring)) same (point ((assembly produc\$5) near3 line) station stage step level time interval period phase)) and (electro\$luminescen\$3 EL LED OLED light\$emitting light\$emission light\$emissive (light near3 (emitting emission emissive)) and (device display panel))	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:16
S9	1582	((((inspect\$3 detect\$3 test\$3) with (tolerance fault\$3 quality performance requirement measurement measuring)) same (point ((assembly produc\$5) near3 line) station stage step level time interval period phase)) and (electro\$luminescen\$3 EL LED OLED light\$emitting light\$emission light\$emissive (light near3 (emitting emission emissive)) and (device display panel))	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:16

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S10	565	((inspect\$3 detect\$3 measur\$5 test\$3) with (tolerance fault\$3 quality station stage step level time interval period phase) and (assembly produc\$5) near3 line) (electro\$luminescen\$3 EL LED OLED light\$emissive (light near3 (emitting emission emissive))) and (device display panel)	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:17
S11	510	((inspect\$3 detect\$3 measur\$5 test\$3) with (tolerance fault\$3 quality performance requirement) same ((assembly produc\$5) near3 line) station stage step level time interval period phase) and (electro\$luminescen\$3 EL LED OLED light\$emissive (light near3 (emitting emission emissive))) and (device display panel)	EPO; JPO; DERWENT	OR	ON	2006/01/23 16:17
S12	331	((inspect\$3 detect\$3 measur\$5 test\$3) with (tolerance fault\$3 quality performance requirement) same ((assembly produc\$5) near3 line) station stage step level time interval period phase) and (electro\$luminescen\$3 EL LED OLED light\$emissive (light near3 (emitting emission emissive))) and (device display panel)	EPO; JPO; DERWENT	OR	ON	2006/01/23 17:52
S13	1	2003-738466.NRAN.	DERWENT	OR	ON	2006/01/23 17:37
S14	1	2005-723969.NRAN.	DERWENT	OR	ON	2006/01/23 17:44
S15	5	"2001291585" "2000294372"	EPO; JPO; DERWENT	OR	ON	2006/01/23 17:52
S16	1	2002-008016.NRAN.	DERWENT	OR	ON	2006/01/23 17:51
S17	2057	((inspect\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance fault\$3 quality performance requirement) same ((assembly produc\$5) near3 line) process station stage step level time interval period phase) and ((manufacturer\$3 produc\$4 method format\$3 assembl\$3) same ((electro\$luminescen\$3 EL OLED light\$emissive (light near3 (emitting emission emissive))) with (device display panel)))	US-PGPUB; USPAT	OR	ON	2006/01/23 18:22
S18	3249	((inspect\$3 discover\$3 evaluate\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance error fault\$3 quality performance requirement) same (((assembly produc\$5) near3 line) process station stage step level time interval period phase) and ((manufacturer\$3 produc\$4 method format\$3 assembl\$3) same ((electro\$luminescen\$3 EL OLED light\$emissive (light near3 (emitting emission emissive))) with (device display panel)))	US-PGPUB; USPAT	OR	ON	2006/01/23 18:24

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S19	289	((inspect\$3 discover\$3 evaluat\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance error fault\$3 quality performance requirement)) same (((assembly produc\$5) near3 line) process station stage step level time interval period phase)) and ((manufactur\$3 produc\$4 method format\$3 assembl\$3) same ((electro\$luminescen\$3 EL OLED light\$emitting light\$emission light\$emissive (light near3 (emitting emission emissive))) with (device display panel)) and ("445"/\$.ccls. "427"/\$.ccls. "438"/\$.ccls. "430"/\$.ccls.)	US-PGPUB; USPAT	OR	ON	2006/01/23 20:00
S20	1	"5537054".pn.	US-PGPUB; USPAT	OR	ON	2006/01/23 18:44
S21	7	("3059183" "5377030").PN. OR ("5537054").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 18:49
S22	8	("4398343" "5233291" "5371459" "5537054" "5897378" "5982190" "6194907" "6320401").PN. OR ("6729922").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 18:49
S23	6	("4757255" "5835997").PN. OR ("6194907").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 18:54
S24	10	("5276400" "5371459" "5432461" "5504438").PN. OR ("5982190").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 18:55
S25	28	("5057775" "5081687" "5170127" "5285150" "5363037" "5369432" "5548357" "5614839" "5650844" "5734158" "5781258" "5793221" "5852480" "5914764" "5982190" "5994916" "6033281" "6056448" "6090545" "6140045" "6150833" "6232616" "6249329" "6281701" "6353466" "6417686" "6552563" "RE37847").PN. OR ("6987400").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 18:58
S26	11	("3832632" "5329423" "5342207" "5378982" "5415555" "5434513" "5489804" "5508228" "5764209").PN. OR ("6552563").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 19:01
S27	7	("5285150" "5764209" "5994916" "6191770" "6466882" "6529837" "6552563").PN. OR ("6778156").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/23 19:20

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S28	46	("2809232" "3718842" "4242703" "4400731" "4491868" "4533950" "4899105" "4922309" "4987032" "5015094" "5057695" "5111110" "5113083" "5169672" "5216504" "5239365" "5245326" "5293178" "5326729" "5333610" "5339093" "5444329" "5450220").PN. OR ("5764209").URPN.	US-PGPUB; USPAT; USOCR	ON	ON	2006/01/23 19:23
S29	9	("5204617" "5293178" "5504504" "5686959" "5717780" "5764209" "5825196").PN. OR ("5966458").URPN.	US-PGPUB; USPAT; USOCR	ON	ON	2006/01/23 19:43
S30	28	("5057775" "5081687" "5170127" "5285150" "5363037" "5369432" "5548357" "5614839" "5650844" "5734158" "5781258" "5793221" "5852480" "5914764" "5982190" "5994916" "6033281" "6056448" "6090545" "6140045" "6150833" "6232616" "6249329" "6281701" "6353466" "6417686" "6552563" "6552563" "RE37847").PN. OR ("6987400").URPN.	US-PGPUB; USPAT; USOCR	ON	ON	2006/01/23 19:52
S31	116	((inspect\$3 discover\$3 evaluat\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance error fault\$3 quality performance requirement)) same ((assembly produc\$5) near3 line) process station stage step level time interval period phase) and ((manufactur\$3 produc\$4 method format\$3 assembl\$3) with ((flat plasma PDP) with (device display panel)))	EPO; JPO; DERWENT	ON	ON	2006/01/23 20:01
S32	209	((inspect\$3 discover\$3 evaluat\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance defect\$3 error fault\$3 quality performance requirement) same (((assembly produc\$5) near3 line) process station stage step level time interval period phase) and ((manufactur\$3 produc\$4 method format\$3 assembl\$3) with ((flat plasma PDP) with (device display panel)))	EPO; JPO; DERWENT	ON	ON	2006/01/23 20:02
S33	170	((inspect\$3 discover\$3 evaluat\$3 discover\$3 detect\$3 measur\$5 test\$3) with (tolerance defect\$3 error fault\$3 quality performance requirement) with (((assembly produc\$5) near3 line) process station stage step level time interval period phase) and ((manufactur\$3 produc\$4 method format\$3 assembl\$3) with ((flat plasma PDP) with (device display panel))))	EPO; JPO; DERWENT	ON	ON	2006/01/23 20:02
S34	1	1999-546975.NRAN.	DERWENT	ON	ON	2006/01/23 20:16
S35	1	1999-546975.NRAN.	DERWENT	ON	ON	2006/01/23 20:16
S36	1	2000-334380.NRAN.	DERWENT	ON	ON	2006/01/23 20:19
S37	1476	"445"/\$.ccls. and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3) with (tolerance quality performance perform\$3 capacity efficiency operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 producat\$3 producii\$3 producing	US-PGPUB; USPAT	ON	ON	2007/12/08 20:23

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S38	774	S37 not @ad>"200001027"	US-PGPUB; USPAT	OR	ON	2007/12/08 20:23
S39	14	("3329422" "3364728" "3543392" "3807006" "4157206" "4373237" "4374451" "4377890").PN. OR ("4573934").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/12/08 16:07
S40	1514	"445"/\$.ccls. and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic\$3 analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 with (tolerance quality performance\$3 capacity efficiency\$3 operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 production\$3))	US-PGPUB; USPAT	OR	ON	2007/12/08 22:50
S41	789	S40 not @ad>"200001027"	US-PGPUB; USPAT	OR	ON	2007/12/08 23:43
S42	12	("3817592" "4324999").PN. OR ("5482486").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/12/08 21:00
S43	130385	(batch (mass near3 (production manufacture)) and (display panel) and (light (field electron) near3 (emisison emitting emissive emitter source))) ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 with (tolerance quality performance\$3 capacity efficiency\$3 operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 production\$3))	EPO; JPO; DERWENT	OR	ON	2007/12/08 22:52
S44	25	(batch (mass near3 (production manufacture)) and (display panel) and (light (field electron) near3 (emisison emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 with (tolerance quality performance\$3 capacity efficiency\$3 operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 production\$3))	EPO; JPO; DERWENT	OR	ON	2007/12/08 22:58
S45	1891	(display panel) and (light ((field electron) near3 (emisison emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 with (tolerance quality performance\$3 capacity efficiency\$3 operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 production\$3))	EPO; JPO; DERWENT	OR	ON	2007/12/08 22:57
S46	1988	(display panel) and (light ((field electron) near3 (emisison emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 with (tolerance quality performance\$3 capacity efficiency\$3 operat\$3)) and (assembl\$3 manufact\$3 fabricat\$3 production\$3))	EPO; JPO; DERWENT	OR	ON	2007/12/08 22:58

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S47	27	(batch (mass near3 (production manufacture)) and (display panel) and (light ((field electron) near3 (emisson emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3) with (tolerance quality performance perform\$3 capacity efficiency efficay operat\$3)) and (assembl\$3 manufact\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/08 23:35
S48	40	(batch mass) and (display panel) and (light ((field electron) near3 (emisson emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3) with (tolerance quality performance perform\$3 capacity efficiency efficay operat\$3)) and (assembl\$3 manufact\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/08 23:36
S49	46	(batch mass) and (display panel) and (light ((field electron) near3 (emisson emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3) with (tolerance quality performance perform\$3 capacity efficiency efficay operat\$3)) and (assembl\$3 manufact\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/09 20:40
S50	47	(batch mass) and (display panel) and (light ((field electron) near3 (emisson emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 monitor\$3) with (tolerance quality performance perform\$3 capacity efficiency efficay operat\$3)) and (assembl\$3 manufact\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/08 23:39
S51	761	((batch set cluster bundle plural multiple plurality mass) with (display device panel)) and (light ((field electron) near3 (emisson emitting emissive emitter source))) and ((test\$3 measur\$3 evaluat\$3 examin\$3 determin\$3 diagnostic analiz\$3 prob\$3 samp\$3 inspect\$3 examinat\$3 monitor\$3) with (tolerance quality performance perform\$3 capacity efficiency efficay operat\$3)) and (assembl\$3 manufact\$3 production producing)	EPO; JPO; DERWENT	OR	ON	2007/12/08 23:39
S52	398	S51 not @pd>"20001027"	EPO; JPO; DERWENT	OR	ON	2007/12/09 20:32